

<b>Notice of References Cited</b>	Application/Control No. 10/619,789	Applicant(s)/Patent Under Reexamination CRUMP ET AL.	
	Examiner Devona E. Faulk	Art Unit 2615	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,118,878	09-2000	Jones, Owen	381/72
*	B	US-2004/0258253	12-2004	Wurtz, Michael	381/071.6
*	C	US-6,829,364	12-2004	Andersen et al.	381/323
*	D	US-2004/0258253	12-2004	Wurtz, Michael	381/071.6
*	E	US-6,069,959	05-2000	Jones, Owen	381/71.6
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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